

FORM PTO-1449 (REV. 7-80)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. H-957-04	SERIAL NO.
LIST OF DOCUMENTS CITED BY APPLICANT (Use several sheets if necessary)		APPLICANT T. MATSUURA et al	
		FILING DATE September 25, 2003	GROUP

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE (If Appropriate)
PN	AA	5,026,669	06/25/91	Shinohara			
	AB	5,327,104	07/05/94	Kikushima			
	AC	5,731,231	03/24/98	Miyajima			
	AD	5,973,395	10/26/99	Suzuki et al			
	AE	6,208,020	03/27/01	Minamio et al			
	AF	6,399,423	06/2002	Matsuura et al			
SN	AG	6,208,020	03/2001	Minamio et al			
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATIO YES	NO
PN	AL	11-195743	07/21/99	Japan			<input type="checkbox"/>	<input type="checkbox"/>
PN	AM	2-240940	09/25/90	Japan			<input type="checkbox"/>	<input type="checkbox"/>
	AN						<input type="checkbox"/>	<input type="checkbox"/>
	AO						<input type="checkbox"/>	<input type="checkbox"/>
	AP						<input type="checkbox"/>	<input type="checkbox"/>

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

PN	AR	"Semiconductor Assembling/Testing Technique of '99", Extra Issue of Monthly Semiconductor World, July 27, 1998.					
	AS						
	AT						

EXAMINER

DATE CONSIDERED

8/10/04

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form next communication to applicant.